

Confocal Raman Microscopy and Neutron Reflectometry Profiling of Composition at Polymer-Polymer Interfaces



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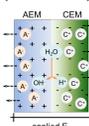
1. Overall Objectives:

- Adapt **confocal Raman microscopy**¹ for spatial profiling ion composition across the **AEM-CEM (anion-exchange membrane / cation-exchange membrane) interface within bipolar polymer membranes**.
- Develop a platform to perform **neutron reflectometry (NR)**² measurements to attain **< 10 nm spatial resolution** in profiling the AEM-CEM interface
- A long term goal is to develop quantitative spectro-electrochemical approaches for the study of structure and reactivity within **catalyst-membrane architectures**.

2. Background

- Bipolar membranes are composed of anion- and cation-exchange phases in adjacent layers (Scheme 1).³

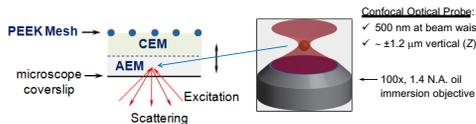
Scheme 1. Bipolar membrane under reverse-bias showing water dissociation at the AEM-CEM interface. (See Ref 3 for details.)



- The membranes enable electrochemical devices to operate with the anode and cathode near the pH optimum of the catalytic reactions, providing a route to improved energy efficiency and cost reduction.
- In a reverse-bias configuration, water dissociation at the AEM-CEM interface can replenish H⁺ consumed at the cathode (e.g., during H₂ generation) and OH⁻ consumed at the anode (e.g., O₂ generation).
- There is interest in a technique to profile the ion-depletion region under bias, and understand the voltage dependence, to guide the development of new membrane materials for improved energy efficiency.

3. Experimental

Confocal Raman Microscopy. The confocal Raman microscope system is described in Ref. 1. The source was a Kr⁺ laser operating at 647.1 nm. A 100x, 1.4 N.A. oil immersion objective brought the laser excitation radiation to a focus within the sample (Scheme 2). Scattered radiation was collected using the same microscope objective. Samples were excited using 3 mW (graphene) or 30 mW (polymer membrane) laser power.



Scheme 2. Confocal Raman sampling configuration of bipolar membrane and characteristics of the optical probe.

3. Experimental (cont.)

Samples Bipolar membrane samples (Fumasep FBM) were provided by Nate Lewis (Caltech). The delicate membranes were backed by a PEEK mesh support (Scheme 2). Prior to measurements, the membranes were exchanged in 0.5 M NaCl or 0.1 M NaClO₄, as indicated. Single layer graphene (SLG) deposited on glass microscope coverslips (SLG/SiO₂) were provided by Steve Creager (Clemson University).

4. Results and Discussion:

A. Confocal Raman Probe Beam Profiling

- To determine spatial resolution limits, it was necessary to measure the intensity profile along the vertical (Z-) axis of the confocal Raman probe beam.
- The profile was measured by stepping through a SLG/SiO₂ interface (Figs 1-2). (See Ref 1 for details)

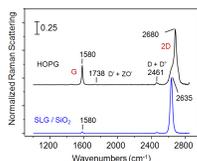


Fig. 1. Raman scattering from highly ordered pyrolytic graphite (HOPG, top) and single layer graphene (SLG) on SiO₂ (bottom) excited at 647.1 nm using 3 mW power. Peak assignments are according to Ref. 4. To aid comparison, each spectrum is normalized to its 2D peak intensity.

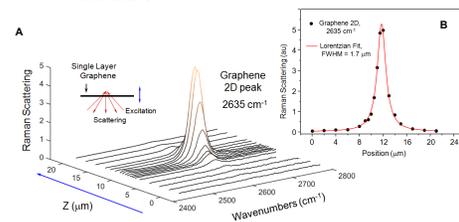


Fig. 2. (A) Raman scattering from single layer graphene on SiO₂ (microscope coverslip) recorded as a function of the confocal probe height, Z, relative to the graphene layer. Z = 0 μm is ~12 μm below the coverslip. The peak intensity is maximum when the confocal probe volume central region overlaps the graphene layer. (B) The 2D peak height as a function of Z (points). The red line shows the fit to the Lorentzian function representing the confocal probe Z-dimension profile.¹

D. Strategies for In-Situ Characterization

- Confocal Raman microscopy:** A microscope-stage mountable in-situ spectroelectrochemical cell⁶ is being tested and adapted (see below).
- NR:** NIST capabilities for performing in-situ NR spectro-electrochemistry are being explored (see Panel 7).

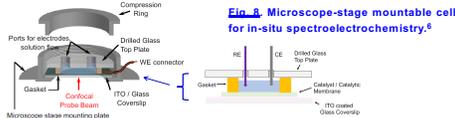


Fig. 3. Microscope-stage mountable cell for in-situ spectroelectrochemistry.⁶

B. Application to Bipolar Membranes

- Spectra recorded during a confocal Raman depth profile are shown in Fig. 3, while Fig. 4 plots the response of the unique CEM-phase marker.
- The change in CEM-phase marker is less than the limiting instrument response, indicating a few micron gradient in ionomer composition across the interface.
- FumaTech confirmed a few micron chemical gradient exists at the AEM-CEM interface, due to intentional roughening and addition of a water-splitting catalyst.⁵

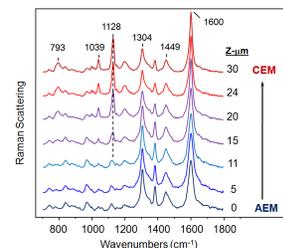


Fig. 3. Confocal Raman spectra collected at points in the vicinity of the AEM-CEM interface of a Fumasep FBM membrane. Spectra were recorded immediately following ion exchange in 0.5 M NaCl.

At Z = 0, the confocal probe volume is positioned within the AEM phase and ~15 μm below the AEM-CEM interface. Laser power = 30 mW.

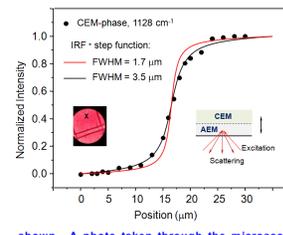


Fig. 4. Plot of the unique CEM-phase marker (1128 cm⁻¹ band) in Figure 3 spectra as a function of measurement position. The solid lines are the convolution of the confocal probe volume Z-profile (IRF) with a step function representing an atomically smooth AEM-CEM junction. Responses for the limiting IRF measured with SLG (red) and IRF derived from fitting the points (black) are shown. A photo taken through the microscope eyepiece is included as an inset and shows the region of beam focus ("X") and segment of PEEK mesh.

- Self-modeling curve resolution (SMCR) applied to a spectral dataset (Fig. 5) associates ClO₄⁻ with the AEM-phase (assigns the features to a single pure component).
- Traces of ClO₄⁻ are detected in the CEM-phase within a few micrometers of the AEM-CEM boundary, consistent with a slight gradient in polymer composition at the interface.

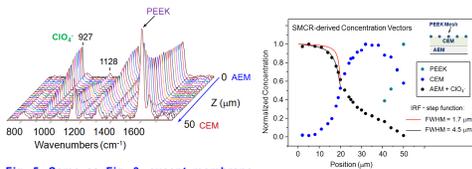


Fig. 5. Same as Fig. 3, except membrane was exchanged in 0.1 M NaClO₄ followed by rinsing in DI water for 48 hrs. The ClO₄⁻ band (927 cm⁻¹) is evident, and PEEK features begin to appear at long distances into the CEM-phase.

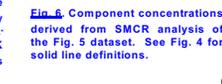


Fig. 6. Component concentrations derived from SMCR analysis of the Fig. 5 dataset. See Fig. 4 for solid line definitions.

C. Neutron Reflectometry (NR) Characterization

- Provides ca. 1 nm spatial resolution in depth profiling.²
- Strategy:** prepare model AEM-CEM interfaces on NR substrates (e.g., Si) by sequential spin-casting of the AEM and CEM polymers; Use deuterium-labeled mobile tetraalkylammonium ions for contrast enhancement.
- Perform NR using in-situ spectroelectrochemistry capabilities at the NIST-Center for Neutron Research

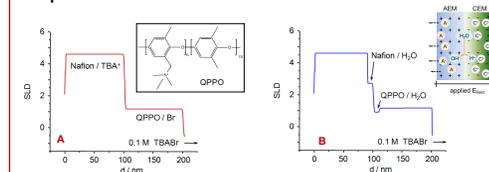


Fig. 7. Calculated scattering length density (SLD) profiles for reflection from a Nafion/QPPO interface (A) without and (B) with an electric field applied.

5. Conclusions and Directions:

- Confocal Raman microscopy** enables quantitative **depth-profiling of composition** within layered membrane materials when the instrument response that limits spatial resolution is known; SLG/SiO₂ provides a robust standard for IRF estimation.¹
- In profiling composition across the bipolar membrane AEM-CEM interface, **spatial resolution** was limited to a few μm but was sufficient to detect the confirmed⁵ component variation.
- Ongoing experiments are exploring (1) strategies for in-situ measurements at the AEM-CEM interface and (2) **NR** as a means to attain **nanoscale** (ca. 1 nm) spatial resolution.

6. References:

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